Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/669,805	CRAIGHEAD, MATTHEW J.
Examiner	Art Unit

Christopher B. Shin

2181

SEARCHED					
Class	Subclass	Date	Examiner		
710	22-28,52- 56	6/13/2007	CS .		
711	202-209	6/13/2007	cs		
•					
		•			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
710	22,56				
711	208				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
PLUS	6/13/2007	cs	
PALM for double patenting	6/13/2007	cs	
EAST (USPGPUB,USPAT,USOCR,FPRS,E PO,JPO,DERWENT,IBMTDB)	6/13/2007	cs	
·	i		
		_	